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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Complete if Known					
			Application Number		10/65	5,239		
			Filing Date		Septer	mber 8, 2003		
			First Named Inventor		Hisasl	ni OHTANI et al.		
			Group Art Unit		2818			
			Examiner Name		D. Le			
Sheet	1	[•	of I		Attorney Docket Number		0756-	7198
				L	J.S. PATENT DOCUMENT	rs		
xaminer nitials*	Cite No.	U.S. Pa	iteni Document	Nam	e of Patentee or Applicant of Cited	Date of Publicat Docum	ent	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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¹ Unique citation designation number. 2 Applicant is to place a check mark here if English language Translation is attached.

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TATEO	INFORMATION DISCLOSURE			Application Number	Based es S.N. 10/814,693 /0/	656239
				Filling Date	August 9, 2002 .]
STAT	STATEMENT BY APPLICANT (late as many sheets as accessary)		First Named Inventor HISASHI OHTANI et			
l			Group Art Unit	2826 2818		
1			Examiner Name	Tan-Tres D. LE]	
Shoci	ı	et	1	Attorney Docket Number	0756-7198	

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Substitute	for form 1449A/PTO			Complete if Known			
TATEO	DMATION I	MILEO IOSIDE	Application Number	(Besedon S.N. 10/314,693 10)	\$5623		
	INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Filling Date	August 9, 2002 9 108 200	3		
STAT			First Named Inventor	HISASHI OHTANI et al.]		
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-			Examiner Name	Tan Tran Di LE]		
Sheet	2	5	Attamey Docket Number	0756-7198			
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	de	Wong et al., Characterization of the MIC/MILC Interface and Its Effects on th Performance of MILC Thin-Film Transistors, (IEEE), pp. 1061-1067, May 20	e 00	

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